

TOSHIBA Field Effect Transistor Silicon P-Channel MOS Type (U-MOS IV)

## TPCF8304

Notebook PC Applications

Portable Equipment Applications

Unit: mm

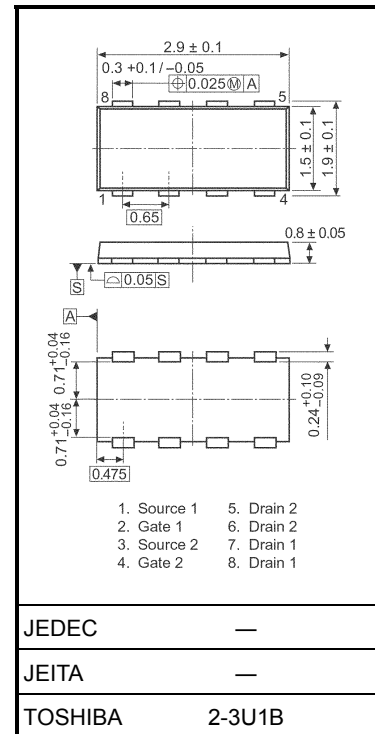
- Low drain-source ON resistance:  $R_{DS(ON)} = 60 \text{ m}\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 5.9 \text{ S}$  (typ.)
- Low leakage current:  $I_{DSS} = -10 \text{ }\mu\text{A}$  (max) ( $V_{DS} = -30 \text{ V}$ )
- Enhancement model:  $V_{th} = -0.8 \text{ to } -2.0 \text{ V}$ ,  
( $V_{DS} = -10 \text{ V}$ ,  $I_D = -1 \text{ mA}$ )

Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

Characteristic		Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	-30	V
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	-30	V
Gate-source voltage		$V_{GSS}$	$\pm 20$	V
Drain current	DC (Note 1)	$I_D$	-3.2	A
	Pulse (Note 1)	$I_{DP}$	-12.8	
Drain power dissipation ( $t = 5 \text{ s}$ ) (Note 2a)	Single-device operation (Note 3a)	$P_D$ (1)	1.35	W
	Single-device value at dual operation (Note 3b)	$P_D$ (2)	1.12	
Drain power dissipation ( $t = 5 \text{ s}$ ) (Note 2b)	Single-device operation (Note 3a)	$P_D$ (1)	0.53	
	Single-device value at dual operation (Note 3b)	$P_D$ (2)	0.33	
Single-pulse avalanche energy (Note 4)		$E_{AS}$	0.67	mJ
Avalanche current		$I_{AR}$	-1.6	A
Repetitive avalanche energy Single-device value at dual operation (Note 2a, 3b, 5)		$E_{AR}$	0.11	mJ
Channel temperature		$T_{ch}$	150	$^\circ\text{C}$
Storage temperature range		$T_{stg}$	-55~150	$^\circ\text{C}$

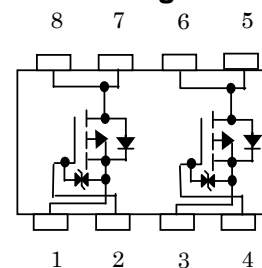
For Notes 1 to 6, see the next page.

Caution: This transistor is an electrostatic-sensitive device. Handle with care.



Weight: 0.011 g (typ.)

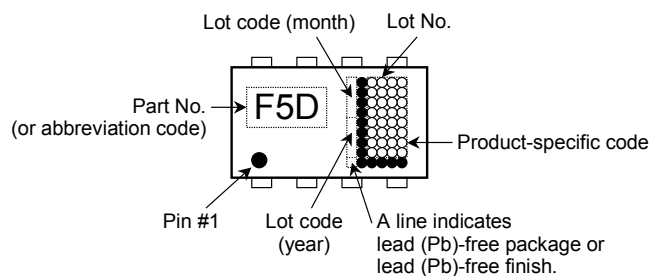
## Circuit Configuration



## Thermal Characteristics

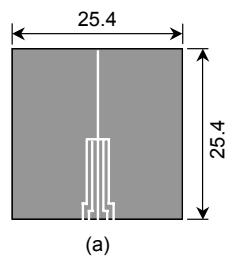
Characteristic		Symbol	Max	Unit
Thermal resistance, channel to ambient ( $t = 5$ s) (Note 2a)	Single-device operation (Note 3a)	$R_{th(ch-a)}(1)$	92.6	$^{\circ}\text{C}/\text{W}$
	Single-device value at dual operation (Note 3b)	$R_{th(ch-a)}(2)$	111.6	
Thermal resistance, channel to ambient ( $t = 5$ s) (Note 2b)	Single-device operation (Note 3a)	$R_{th(ch-a)}(1)$	235.8	$^{\circ}\text{C}/\text{W}$
	Single-device value at dual operation (Note 3b)	$R_{th(ch-a)}(2)$	378.8	

## Marking (Note 6)

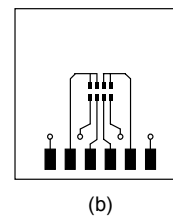


Note 1: Ensure that the channel temperature does not exceed  $150^{\circ}\text{C}$ .

Note 2: (a) Device mounted on a glass-epoxy board (a) (b) Device mounted on a glass-epoxy board (b)



FR-4  
25.4 × 25.4 × 0.8  
(Unit: mm)



FR-4  
25.4 × 25.4 × 0.8  
(Unit: mm)

Note 3: a) The power dissipation and thermal resistance values shown are for a single device. (During single-device operation, power is applied to one device only.)

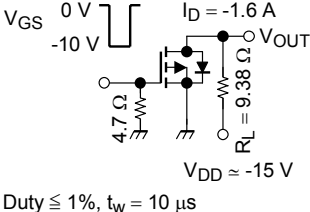
b) The power dissipation and thermal resistance values shown are for a single device. (During dual operation, power is evenly applied to both devices.)

Note 4:  $V_{DD} = -24$  V,  $T_{ch} = 25^{\circ}\text{C}$  (initial),  $L = 0.2$  mH,  $R_G = 25$   $\Omega$ ,  $I_{AR} = -1.6$  A

Note 5: Repetitive rating; pulse width limited by max channel temperature

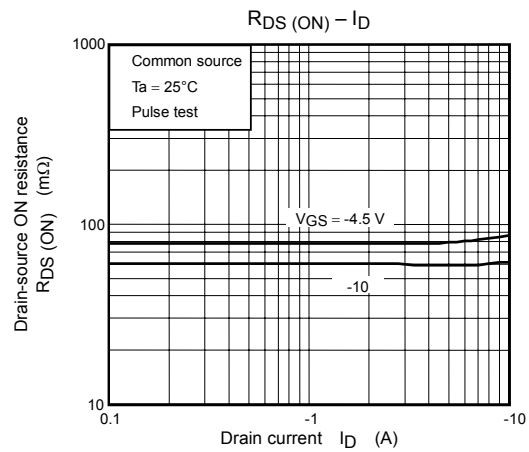
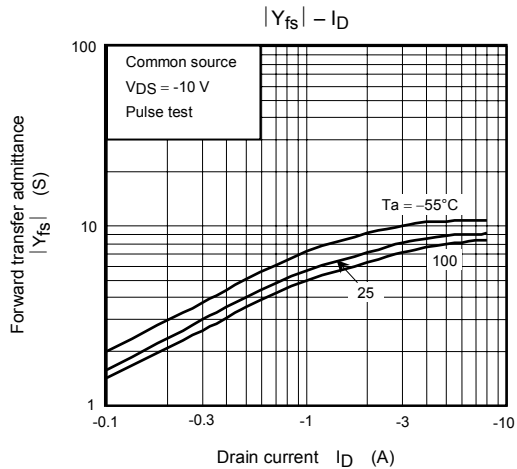
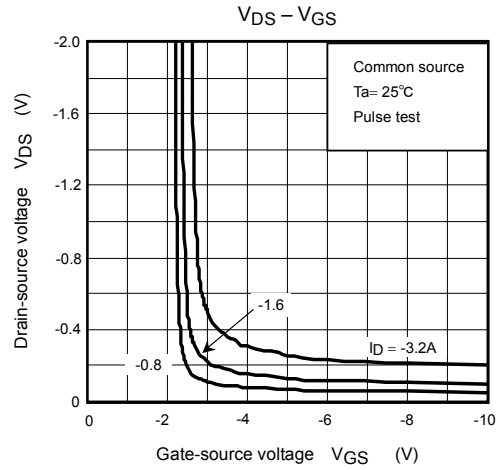
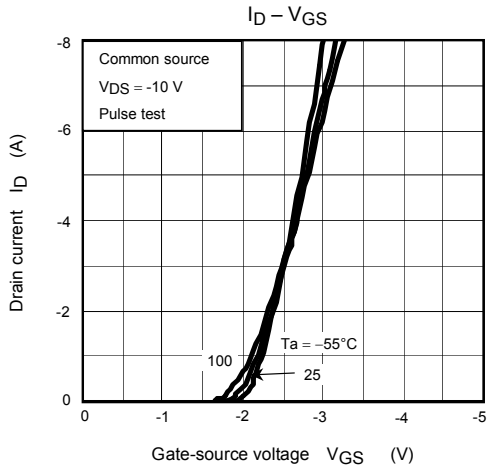
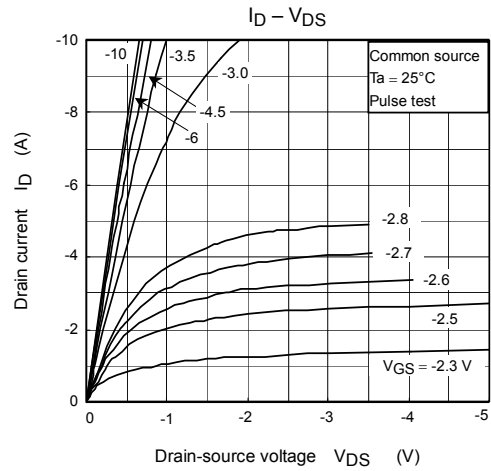
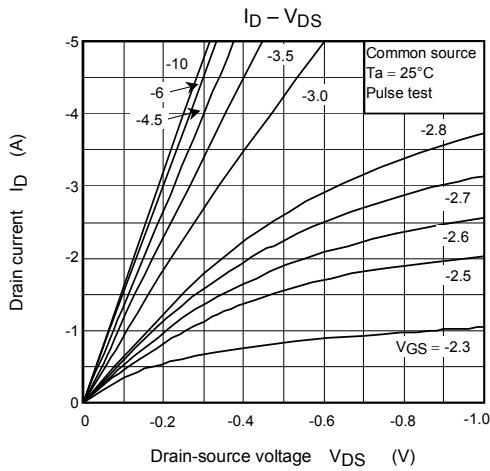
Note 6: ● to the lower left of the Part No. marking indicates Pin 1.

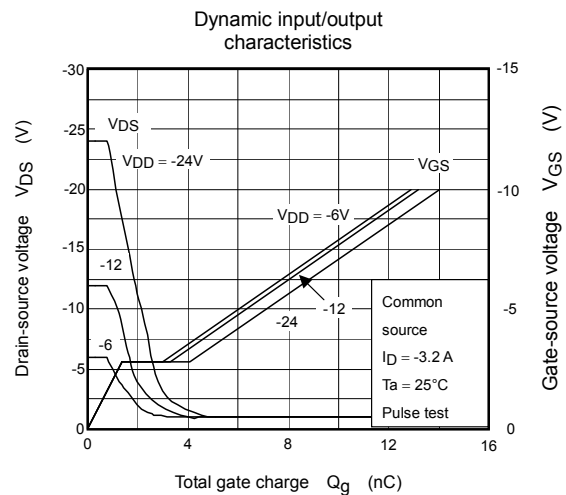
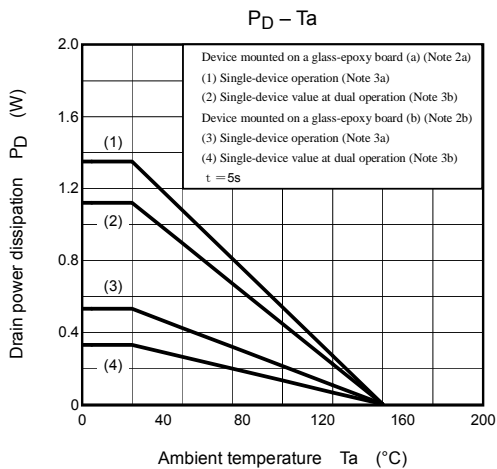
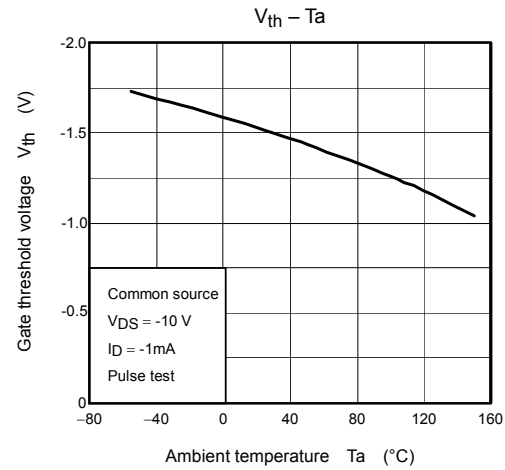
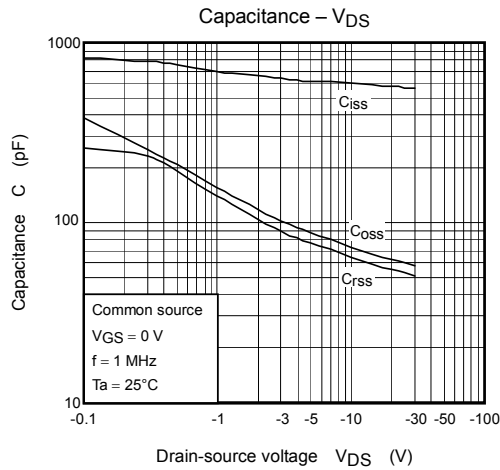
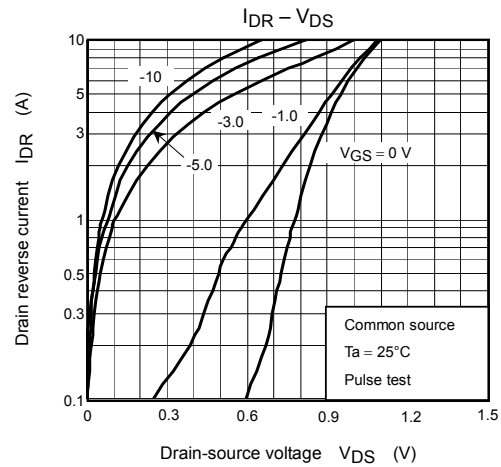
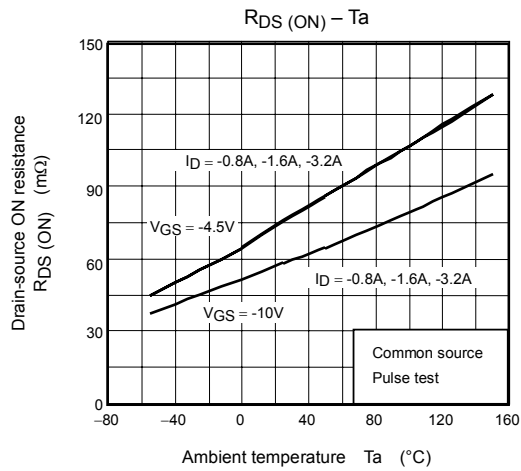
## Electrical Characteristics (Ta = 25°C)

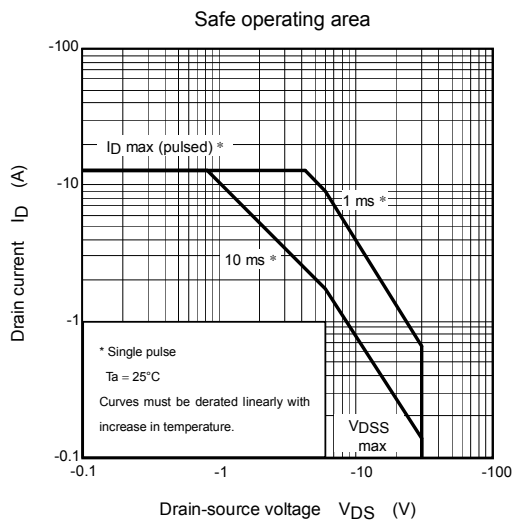
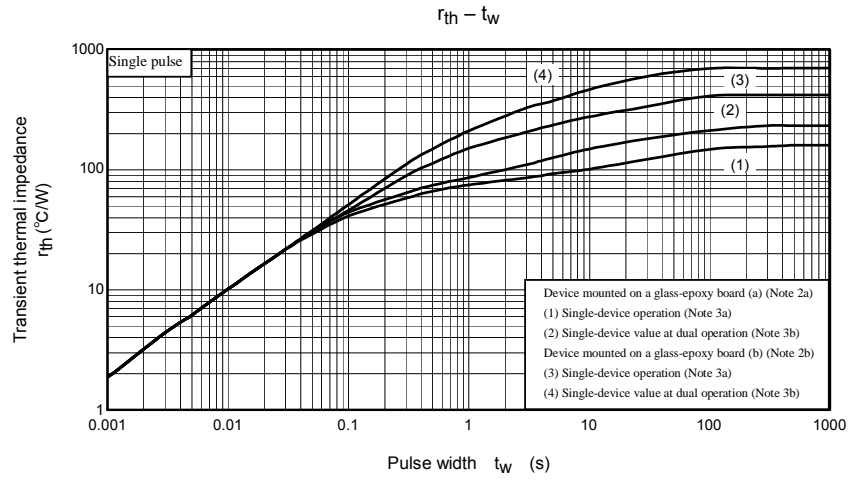
Characteristic		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		$I_{GSS}$	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	—	—	$\pm 10$	$\mu\text{A}$
Drain cut-off current		$I_{DSS}$	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$	—	—	-10	$\mu\text{A}$
Drain-source breakdown voltage	$V_{(BR)DSS}$		$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	-30	—	—	V
	$V_{(BR)DSX}$		$I_D = -10 \text{ mA}, V_{GS} = 20 \text{ V}$	-15	—	—	
Gate threshold voltage		$V_{th}$	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$	-0.5	—	-1.2	V
Drain-source ON resistance	$R_{DS(ON)}$		$V_{GS} = -4.5 \text{ V}, I_D = -1.6 \text{ A}$	—	80	105	$\text{m}\Omega$
	$R_{DS(ON)}$		$V_{GS} = -10 \text{ V}, I_D = -1.6 \text{ A}$	—	60	72	
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = -10 \text{ V}, I_D = -1.6 \text{ A}$	2.9	5.9	—	S
Input capacitance		$C_{iss}$	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	—	600	—	pF
Reverse transfer capacitance		$C_{rss}$		—	60	—	
Output capacitance		$C_{oss}$		—	70	—	
Switching time	Rise time	$t_r$	 <p><math>V_{GS} = 0 \text{ V} \rightarrow -10 \text{ V}</math>  <math>I_D = -1.6 \text{ A}</math>  <math>V_{DD} \approx -15 \text{ V}</math>  <math>R_L = 9.38 \Omega</math>  <math>47 \Omega</math>  <math>V_{OUT}</math>  <math>\text{Duty} \leq 1\%, t_w = 10 \mu\text{s}</math></p>	—	5.3	—	ns
	Turn-on time	$t_{on}$		—	12	—	
	Fall time	$t_f$		—	8.4	—	
	Turn-off time	$t_{off}$		—	34	—	
Total gate charge (gate-source plus gate-drain)		$Q_g$	$V_{DD} \approx -24 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -3.2 \text{ A}$	—	14	—	nC
Gate-source charge 1		$Q_{gs1}$		—	1.4	—	
Gate-drain ("Miller") charge		$Q_{gd}$		—	2.7	—	

## Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min	Typ.	Max	Unit
Drain reverse current	Pulse (Note 1)	$I_{DRP}$	—	—	—	-12.8	A
Forward voltage (diode)		$V_{DSF}$	$I_{DR} = -3.2 \text{ A}, V_{GS} = 0 \text{ V}$	—	—	1.2	V







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